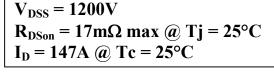
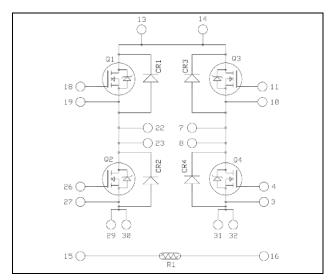


## Full bridge SiC MOSFET Power Module





#### Application

- Welding converters
  - Switched Mode Power Supplies
- Uninterruptible Power Supplies
- Motor control

#### **Features**

#### SiC Power MOSFET

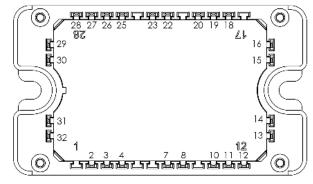
- $Low \; R_{DS(on)}$
- High temperature performance

#### SiC Schottky Diode

- Zero reverse recovery
- Zero forward recovery
- Temperature Independent switching behavior
- Positive temperature coefficient on VF
- Kelvin source for easy drive
- Very low stray inductance
- Internal thermistor for temperature monitoring
- AlN substrate for improved thermal performance



- Outstanding performance at high frequency operation
- Direct mounting to heatsink (isolated package)
- Low junction to case thermal resistance
- Solderable terminals both for power and signal for easy PCB mounting
- Low profile
- Each leg can be easily paralleled to achieve a phase leg of twice the current capability
- RoHS compliant



All multiple inputs & outputs must be shorted together Example: 13/14; 29/30; 22/23 ...

#### All ratings @ $T_i = 25$ °C unless otherwise specified

These Devices are sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.

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#### Absolute maximum ratings (per SiC MOSFET)

Symbol	Parameter		Max ratings	Unit
$V_{ m DSS}$	Drain - Source Voltage		1200	V
Ţ	Continuous Drain Current	$T_c = 25^{\circ}C$	147	
$I_D$	Continuous Drain Current	$T_c = 80$ °C	116	Α
$I_{DM}$	Pulsed Drain current		300	
$V_{GS}$	Gate - Source Voltage		-10/25V	V
$R_{DSon}$	Drain - Source ON Resistance		17	mΩ
$P_{D}$	Maximum Power Dissipation	$T_c = 25^{\circ}C$	750	W

### **Electrical Characteristics** (per SiC MOSFET)

Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit	
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{GS} = 0V$ , $V_{DS} = 120$		20	200	μΑ	
D	Drain – Source on Resistance	$V_{GS} = 20V$	$T_j = 25^{\circ}C$		12.5	17	
R <sub>DS(on)</sub>		$I_{\rm D} = 100 A$	$T_{j} = 175^{\circ}C$		26		mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 30$ m	2	2.6	4	V	
$I_{GSS}$	Gate – Source Leakage Current	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$			·	1.2	μΑ

#### **Dynamic Characteristics** (per SiC MOSFET)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
$C_{iss}$	Input Capacitance	$V_{GS} = 0V$			5576		
$C_{oss}$	Output Capacitance	$V_{DS} = 1000V$			440		pF
$C_{rss}$	Reverse Transfer Capacitance	f = 1MHz			30		
$Q_{g}$	Total gate Charge	$V_{GS} = -5/+20V$			332		
$Q_{\mathrm{gs}}$	Gate – Source Charge	$V_{\text{Bus}} = 800V$			92		nC
$Q_{\text{gd}}$	Gate – Drain Charge	$I_{\rm D} = 100 A$			100		
$T_{d(on)}$	Turn-on Delay Time	V - 2/±20V			21		
$T_{\rm r}$	Rise Time	$V_{GS} = -2/+20V$ $V_{Bus} = 800V$ $I_D = 100A$			19		ns
$T_{d(off)}$	Turn-off Delay Time				50		
$T_{\mathrm{f}}$	Fall Time	$R_L = 8\Omega$ ; $R_G = 10\Omega$			30		
Eon	Turn on Energy	Inductive Switching $V_{GS} = -5/+20V$ $V_{Bus} = 600V$	$T_{j} = 150^{\circ}C$		2.2		mJ
$E_{\text{off}}$	Turn off Energy	$I_{D} = 100A$ $R_{G} = 10\Omega$	$T_{j} = 150^{\circ}C$		1.2		1113
$R_{Gint}$	Internal gate resistance				3.05		Ω
$R_{\text{thJC}}$	Junction to Case Thermal Resistance	e				0.2	°C/W

# **Body diode ratings and characteristics** (per SiC MOSFET) **Symbol** Characteristic Test Conditions

Symbol	Characteristic	Test Conditions		Min	Тур	Max	Unit
$V_{\mathrm{SD}}$	Diode Forward Voltage	$V_{GS} = -5V$	$T_j = 25^{\circ}C$		4		V
		$I_{SD} = 50A$	$T_i = 175$ °C		3.5		V
$t_{rr}$	Reverse Recovery Time				45		ns
Q <sub>rr</sub>	Reverse Recovery Charge				812		nC
I <sub>rr</sub>	Reverse Recovery Current				27		A
	·	•					



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### SiC schottky diode ratings and characteristics (per SiC diode)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
$V_{RRM}$	Peak Repetitive Reverse Voltage					1200	V
$I_{RRM}$	Reverse Leakage Current	se Leakage Current $V_R$ =1200 $V$	$T_j = 25^{\circ}C$		70	400	μA
1RRM	Reverse Leakage Current		$T_{j} = 175^{\circ}C$		130	800	μ1
$I_F$	DC Forward Current		Tc = 100°C		40		A
$\mathbf{V}_{-}$	$V_F$ Diode Forward Voltage $I_F = 40A$	I = 40A	$T_i = 25^{\circ}C$		1.5	1.8	V
<b>v</b> F		$T_i = 175^{\circ}C$		2.2	3	V	
Qc	Total Capacitive Charge	$I_F = 40A, V_R = 1200V$ di/dt = 1000A/ $\mu$ s			198		nC
С	Total Conscitous	$f = 1MHz, V_R = 400V$	=400V		186		ъE
	Total Capacitance $f = 1M$		= 800V		134		pF
$R_{thJC}$	Junction to Case Thermal Resistance					0.55	°C/W

#### Temperature sensor NTC (see application note APT0406 on www.microsemi.com).

Symbol	Characteristic		Min	Typ	Max	Unit
R <sub>25</sub>	Resistance @ 25°C			50		kΩ
$\Delta R_{25}/R_{25}$				5		%
B <sub>25/85</sub>	$T_{25} = 298.15 \text{ K}$			3952		K
$\Delta B/B$		$T_C=100$ °C		4		%

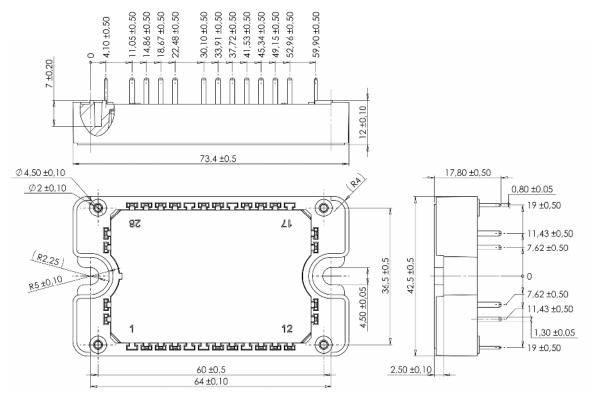
$$R_{T} = \frac{R_{25}}{\exp\left[B_{25/85}\left(\frac{1}{T_{25}} - \frac{1}{T}\right)\right]}$$
 T: Thermistor temperature R<sub>T</sub>: Thermistor value at T

### Thermal and package characteristics

Symbol	Characteristic			Min	Max	Unit
$V_{ISOL}$	RMS Isolation Voltage, any terminal to case t =1 min, 50/60Hz					V
$T_{\mathrm{J}}$	Operating junction temperature range				175	
$T_{JOP}$	Recommended junction temperature under switching conditions			-40	T <sub>J</sub> max -25	°C
$T_{STG}$	Storage Temperature Range				125	C
$T_{\rm C}$	Operating Case Temperature			-40	125	
Torque	Mounting torque	To heatsink	M4	2	3	N.m
Wt	Package Weight				110	g



### Package outline (dimensions in mm)



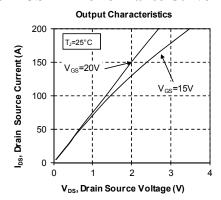
See application note 1906 - Mounting Instructions for SP3F Power Modules on www.microsemi.com

www.microsemi.com

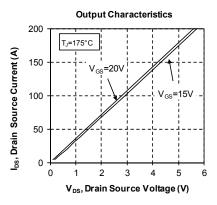
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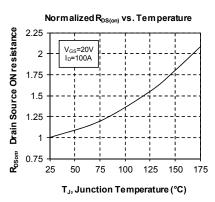


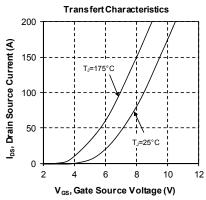
### **Typical SiC MOSFET Performance Curve**

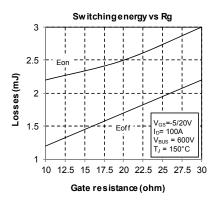


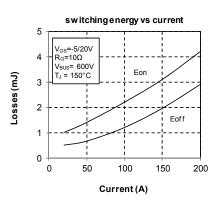
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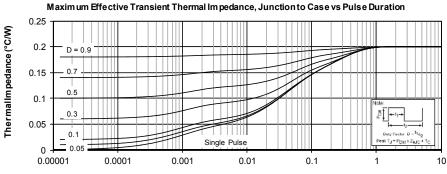








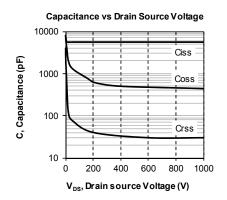


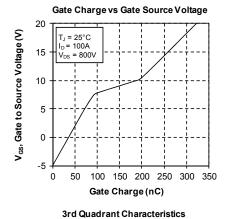


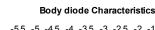
rectangular Pulse Duration (Seconds)

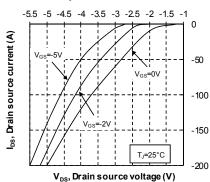


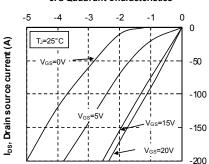
#### Power Matters."





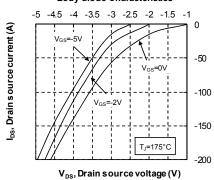


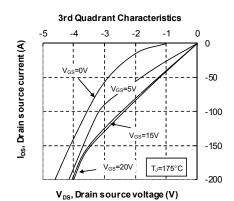




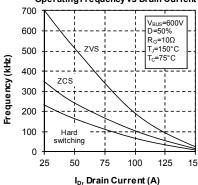
V<sub>DS</sub>, Drain source voltage (V)







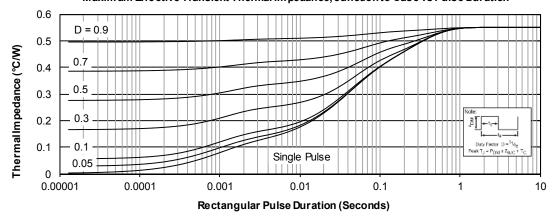
#### Operating Frequency vs Drain Current

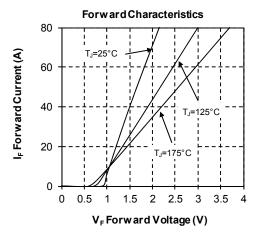


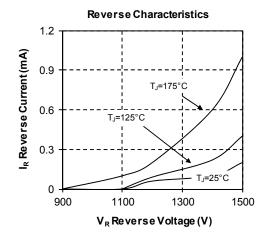


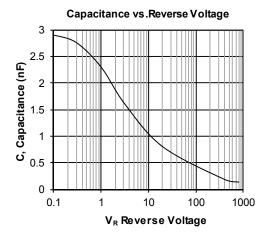
#### Typical SiC diode Performance Curve

#### Maximum Effective Transient Thermal Impedance, Junction to Case vs Pulse Duration









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